

## **Master/bachelor thesis**

in the subject area of

### **Table-top near X-ray absorption edge fine structure measurements**

Near X-ray absorption edge fine structure measurements can provide detailed information on materials. In particular, they give access to the composition of materials and the chemical state of specific atomic species within the material. First measurements with state-of-the-art table-top soft X-ray sources shall demonstrate the potential of this technique at the silicon L-edge at ~100 eV and the carbon K-edge at ~280 eV.

Please, send your application preferably by email to

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